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Surface chemical analysis — Auger electron spectroscopy — Description of selected instrumental performance parameters

Analyse chimique des surfaces — Spectroscopie d'électrons Auger — Description de certains paramètres relatifs à la performance instrumentale

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Foreword

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The committee responsible for this document is ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 7, *Electron spectroscopies*.

This second edition cancels and replaces the first edition (ISO 15471:2004), of which it constitutes a minor revision with the following modifications:

— addition of a Bibliography;

— minor editorial changes to the text.

Introduction

Auger electron spectrometers (AESs) and scanning Auger electron microscopes (SAMs) are produced by many manufacturers throughout the world. While the basic principles of the AES analytical method in each instrument are the same, the specific designs of the instruments and the way that performance specifications are provided differ widely. As a result, it is often difficult to compare the performance of instruments from one manufacturer with those from another. This International Standard provides a basic list of items devised to enable all Auger electron spectrometers to be described in a common manner. This International Standard is not intended to replace the manufacturer's specification, which may extend to 30 or more pages. It is intended that, where certain items are contained in that specification, there are agreed and defined meanings to those items.